

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/626,122	SOHN, SUSAN	
Examiner	Art Unit	
Yaima Campos	2185	

SEARCHED			
Class	Subclass	Date	Examiner
			·

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
711	112	5/10/2006	YC
711	170	5/10/2006	YC
711	173	5/10/2006	YC

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EIC Fast and Focused	5/10/2006	YC
PALM and EAST inventor name search	5/10/2006	YC
EAST text search	5/10/2006	YC
Text search within subclasses 711/112,170,173	5/10/2006	YC
EAST text search for interference	5/10/2006	YC
Consulted Primary Examiners Nasser Moazzami and Pierre-Miche Bataille on Allowability issues	5/10/2006	YC

Search Notes



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